

“High resolution electron microscopy and X-ray photoelectron spectroscopy studies of heteroepitaxial $\text{Si}_x\text{Ge}_{1-x}$ alloys produced through laser induced processing”. Frangis N, van Landuyt J, Lartiprete R, Martelli S, Borsella E, Chiussi S, Castro J, Leon B, Applied physics letters **72**, 2877 (1998). <http://doi.org/10.1063/1.121487>